

Development of a telescopic spectral reflectance measurement system and image analysis software for lunar spectroscopic geology

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The telescopic spectral reflectance measurement system for the moon has been constructed by assembling amateur astronomical apparatuses, band-pass filters and a cooling CCD device. The system includes image analysis software with graphical user interface. The system enables us to make FeO and TiO₂ chemical distribution maps of the near side of the moon. It is useful not only for the preliminary study for lunar science but also for an introduction to lunar geology.